

FIG. 1 is a schematic diagram of a system for measuring the thickness of a material. The system includes a light source 1, a collimating lens 2, a sample 3, a detector 4, and a control unit 5. The light source 1 emits a beam of light 6 which is collimated by lens 2 and directed at sample 3. The light passing through sample 3 is detected by detector 4. The control unit 5 is connected to detector 4 and is used to process the detected signal. A dashed box 12 indicates a region of interest on the sample. A double-headed arrow X indicates the direction of light travel.

FIG. 1

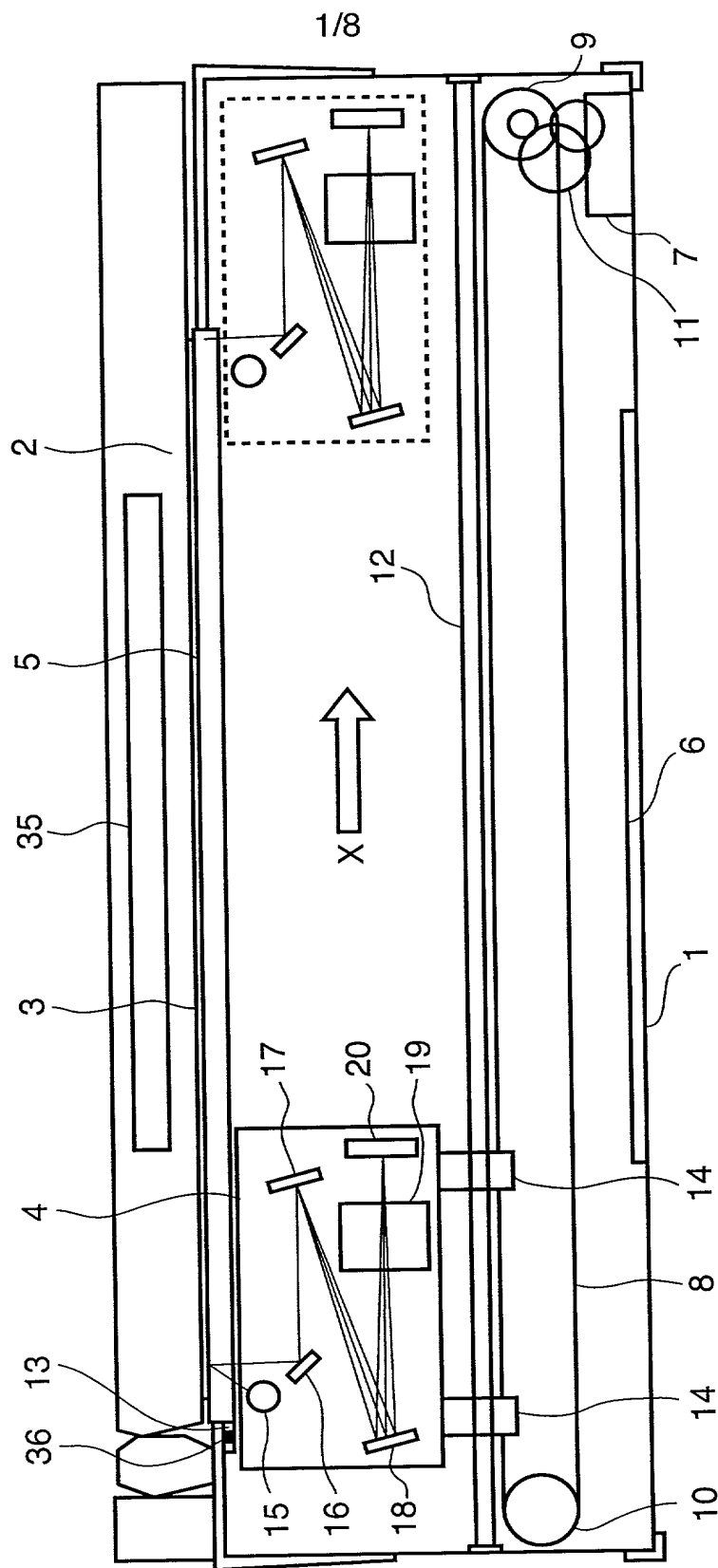


FIG. 2

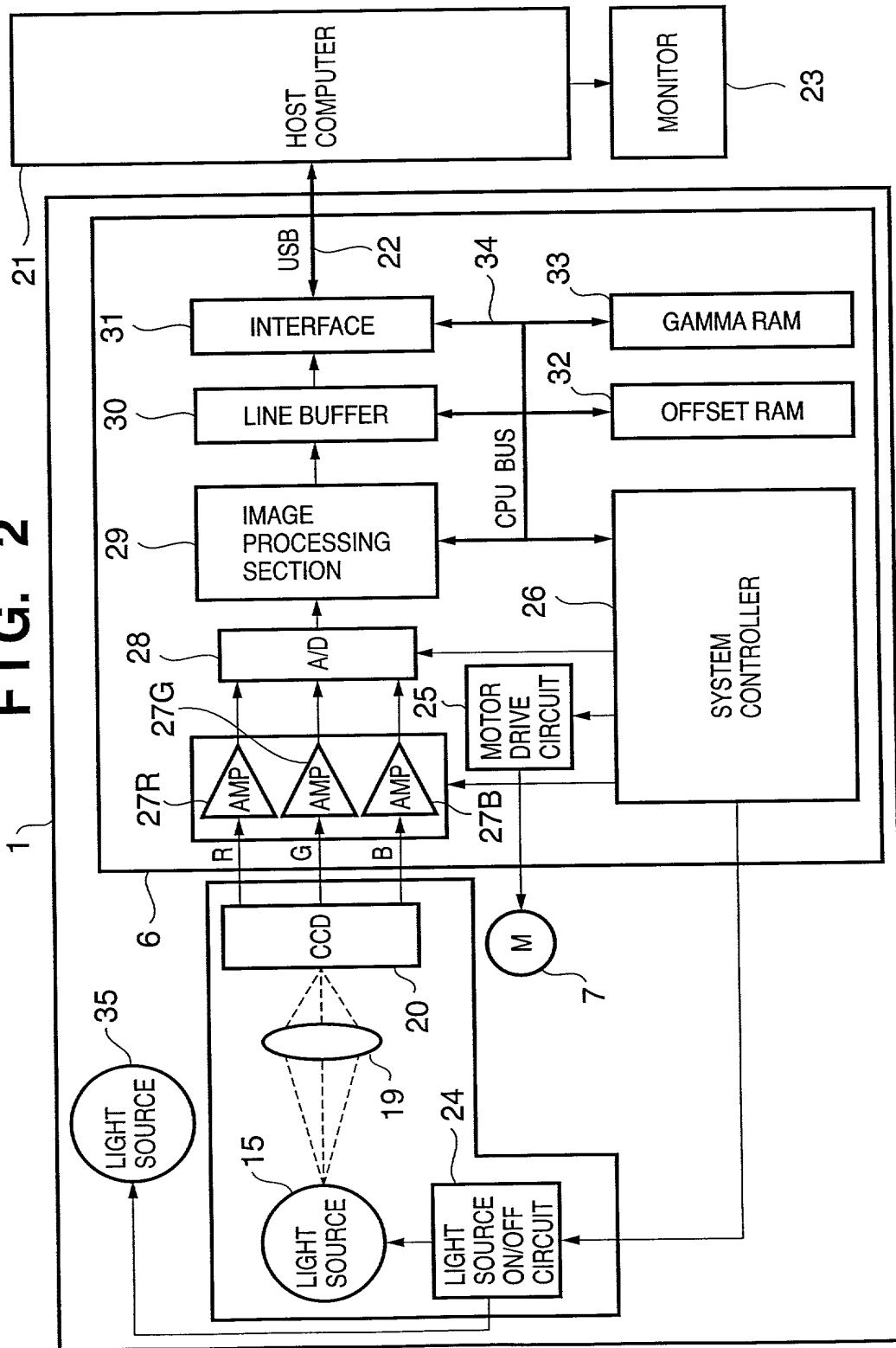


FIG. 3

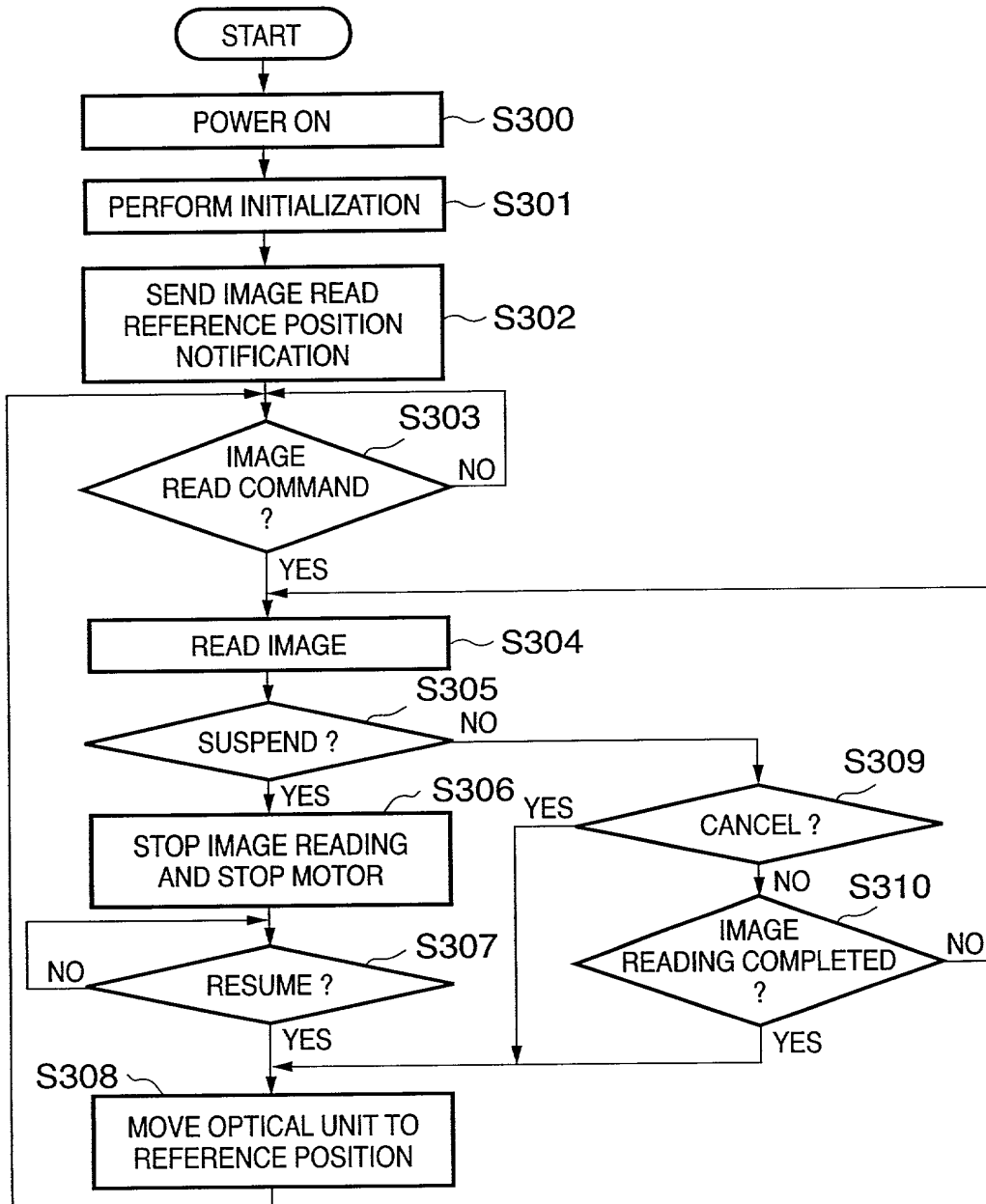


FIG. 4

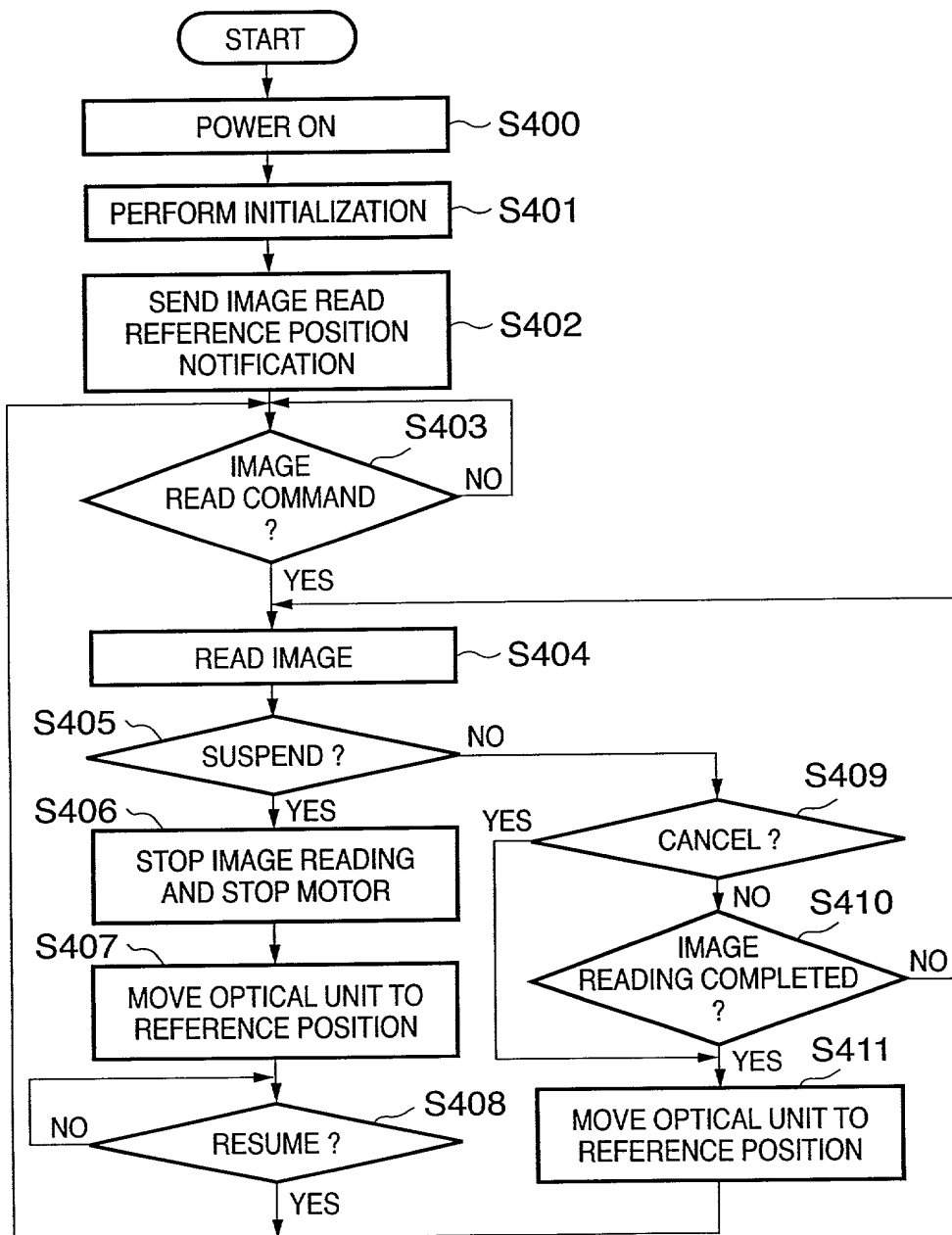


FIG. 5

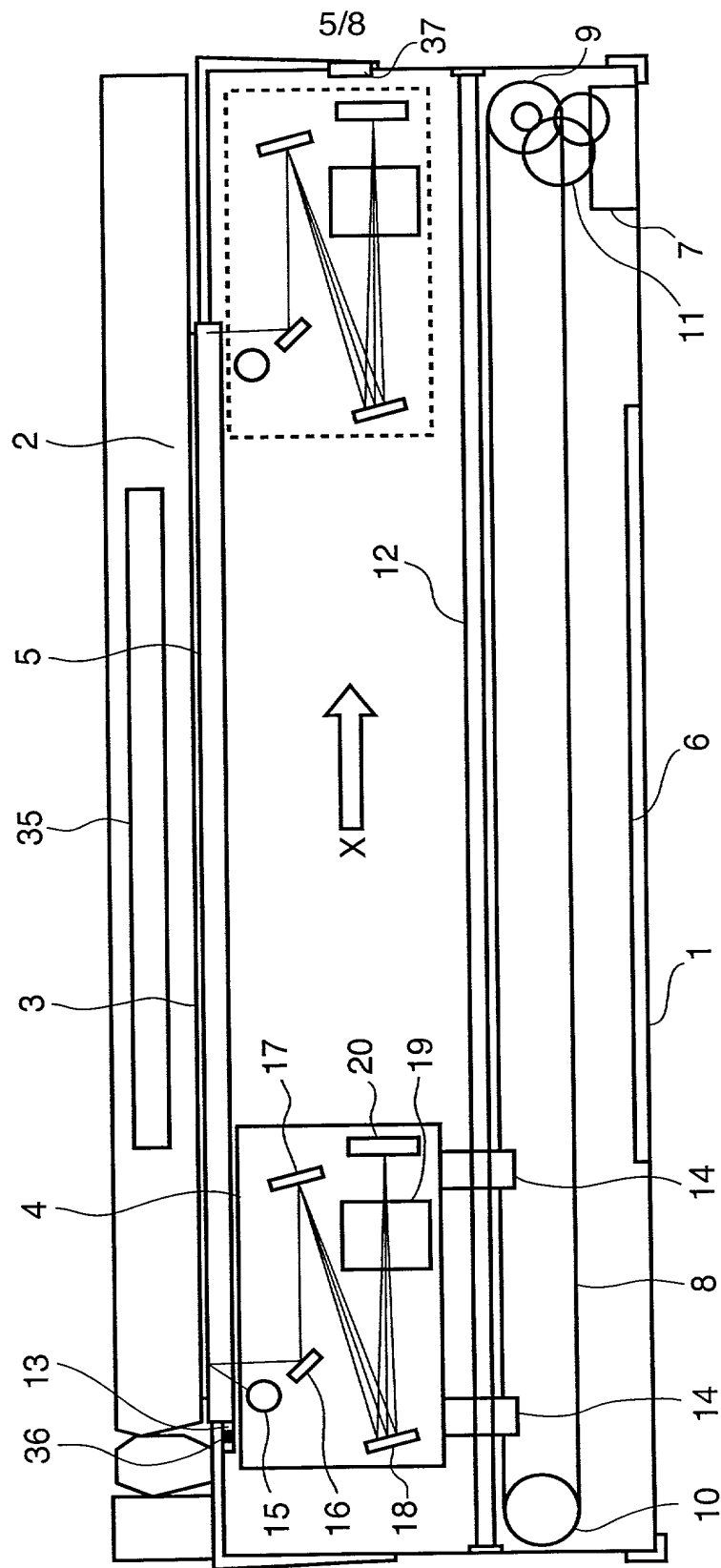


FIG. 6

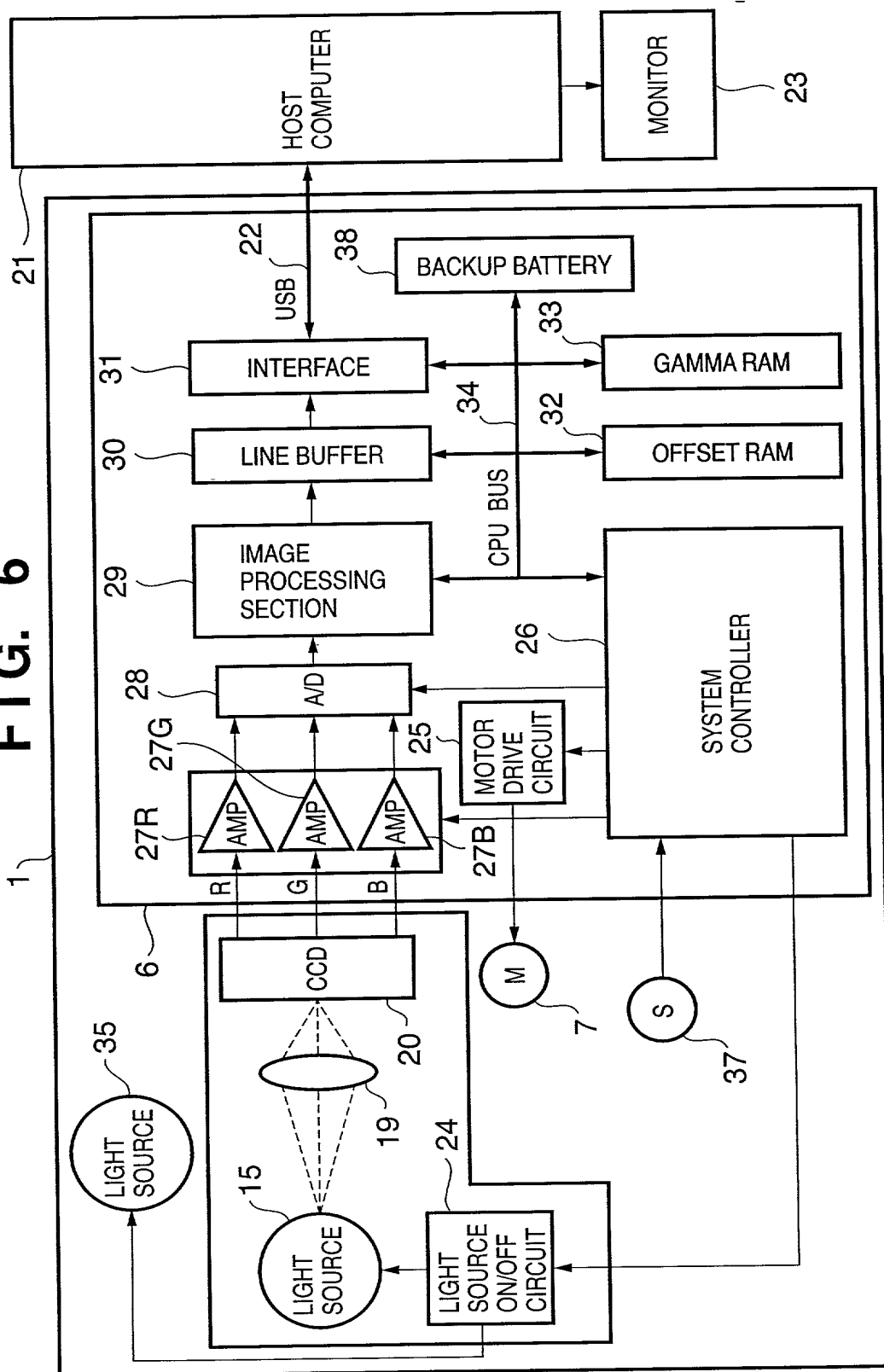
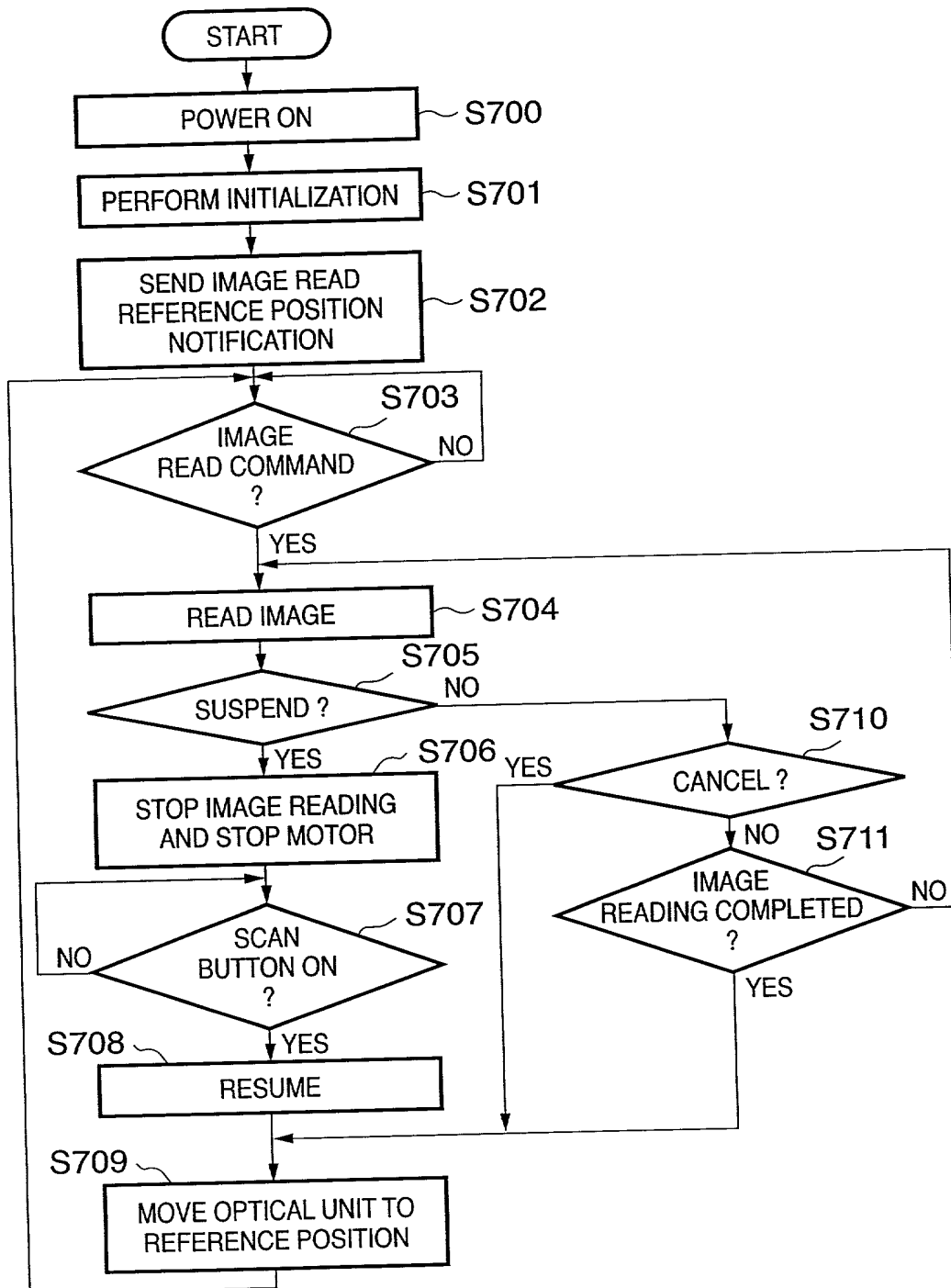


FIG. 7



**FIG. 8**